

Application No.: 10/051,056

Docket No.: 843.41106X00

**IN THE TITLE:**

Please amend the Title as follows:

~~SEMICONDUCTOR DEVICE, METHOD OF MEASURING THE SAME, AND~~  
~~METHOD OF MANUFACTURING THE SAME~~ A SEMICONDUCTOR DEVICE TO  
PROVIDE A PLURALITY OF TEST ELEMENT GROUPS (TEGs) IN A SCRIBE  
REGION